

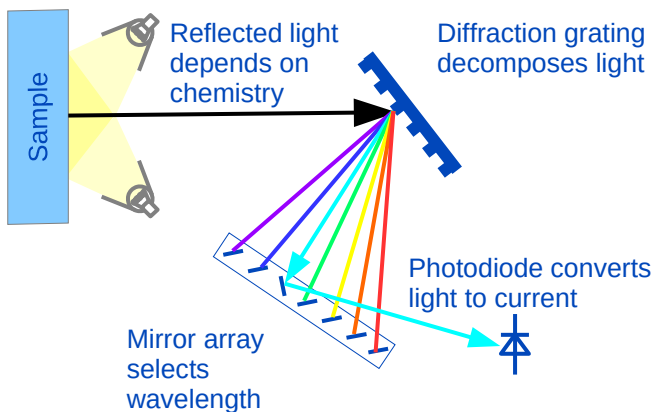
### Material Analysis with NIR Spectrometry

- Measurement of reflected light
- compact and easy to use
- low noise
- height dynamic range



## Working Principle

LuxFlux uses TI's DLP® Technology in conjunction with an InGaAs photodiode for a low-noise spectrometer with high dynamic range



## Specification

Spectral Range	900 - 1700 nm
Working Distance	<2 mm
Spectral Resolution	10 nm
Accuracy	±2 nm
Entrance Slit	25 µm
Signal to Noise Ratio	> 5000
Usable Pixels	583
Time per Scan	< 1 sec
Detector	InGaAs, 1 mm Diameter
A/D Converter	24 Bit / 30 kHz
Light Source	Tungsten-Halogen
Temperature Range	10 – 40 °C
Dimensions	76mm x 82mm x 27mm
Weight	87 g
Power Supply	5V, 500mA via USB
Operating System	Windows 7 + 10, OSX 10.12, Linux

## Options

Different measurement heads available:

- Fiber optics (SMA905)
- Cuvette holder for transmission measurement

All modules available without housing

## Calibration

All devices are factory calibrated using a SRM-2036 standard for wavelength calibration and a Spectralon white standard for photometric calibration.